

CONTENTS

<i>Preface</i>	xi
<i>Future Contributions</i>	xv
<i>Contributors</i>	xix
1. Invariant Quantum Wave Equations and Double Space-Time	1
Claude Daviau	
1. Introduction	3
2. Dirac Equation	7
3. The Homogeneous Nonlinear Wave Equation	25
4. Invariance of Electromagnetic Laws	37
5. Electro-Weak and Electro-Strong Interactions	55
6. Other Consequences	78
7. Appendix A–Clifford Algebra	97
8. Appendix B–Calculations in Pauli Algebra	113
Acknowledgments	134
2. In-Situ and Correlative Electron Microscopy	137
Niels de Jonge	
Introduction	137
Session 1 Studying Carbon-Based Materials	
In-situ Electron Microscopy of Graphene and Related Carbon Nanomaterials	140
J.-A. Rodríguez-Manzo, O. Cretu, F. Banhart	
Different Mechanisms of Graphene Wall Nucleation on Fe and Ni Particles	142
J.-L. Maurice, Z. B. He, C. S. Cojocaru	
Session 2 Correlative Fluorescence and Electron Microscopy	
Imaging Dynamic Biological Systems Using Correlative Light and Electron Microscopy	146
J. Briggs	

Toward Exploring the 3D Supramolecular Architecture of Centrosomes In-Situ	147
J. Mahamid, A. Hyman, W. Baumeister	
The CryoCapsule: a New Versatile Tool for Fast and Reliable Correlative Light to Electron Microscopy	148
X. Heiligenstein, J. Heiligenstein, C. Antony, J. Salamero, G. Raposo	
Session 3 Electron Microscopy of Biological Specimens in their Native Environment	
Electron-light Correlative Microscopy in Open Solution by Atmospheric Scanning Electron Microscope (ASEM)	152
T. Ebihara, H. Nishiyama, M. Suga, C. Sato	
Visualization of EGF Receptor Dimers on Wet and Intact Eukaryotic Cells in an Environmental Scanning Electron Microscope	155
D. Peckys, M. Eder, U. Werner, N. de Jonge	
Type VII Secretion System of Mycobacteria: Toward Visualization of Nanomachines in their Native Cellular Environment Using Electron Cryo-microscopy	158
P. J. Peters	
Session 4 Imaging Growth of Nanomaterials in Liquid	
Real-Time Imaging of Growth and Transformation Dynamics of Nanocrystals	161
H. Zheng	
Biomimetic Synthesis of Silica Structures	164
M. W. P. van de Put, C. C. M. Carcouët, N. de Jonge, M. J. Boerakker, G. de With, N. A. J. M. Sommerdijk	

Unraveling the CaCO₃ Mesocrystal Formation Mechanism Including a Polyelectrolyte Additive using in-situ TEM and in-situ AFM 165

P. J. M. Smeets, D. Li, M. H. Nielsen, K. R. Cho,
N. A. J. M. Sommerdijk, J. J. De Yoreo

Session 5 In-Situ Studies of Electronic Materials and Metals

In-situ Transmission Electron Microscopy 169

H. W. Zandbergen

In-situ Deformation Analysis of Nanocrystalline Metals by Quantitative ACOM-STEM 172

C. Kübel, A. Kobler, H. Hahn

Session 6 Studying Electrochemistry with Liquid Cell Electron Microscopy

Application of In-situ Electrochemical Liquid Cells for Electrical Energy Storage Research 176

R. R. Unocic, X.-G. Sun, D. H. Alsem, N. J. Salmon, S. Dai,
N. J. Dudney, K. L. More

Correlating Light Microscopy and Electron Microscopy for Measuring Microstructural Evolution During Electrochemical Deposition 179

F. M. Ross, M. den Heijer, M. J. Williamson, D. Steingart

Session 7 Poster Session

Correlated Fluorescence and Electron Microscopy in Cytotoxic T Lymphocytes of a Synaptobrevin2-mRFP Knockin Mouse 184

C. Schirra, Varsha Pattu, Ulf Matti, Ludwig Edelmann, Anneka Bost,
Monika Dudenhöffer-Pfeifer, Mahantappa Halimani, Lisa Weins, Jens Rettig

Utilization of "Shuttle & Find" for Uptake Analysis of Substructured, Rodshaped Microparticles by Alveolar Macrophages 187

M. Hittinger, C. Tscheka, C.-M. Lehr, M. Schneider, N. Daum

Scanning Transmission Electron Microscopy (STEM) of Whole Eukaryotic Cells in Liquid	189
N. de Jonge, D. B. Peckys	
Biom mineralization—Insights from Light Microscopy and Electron Microscopy Studies	192
Marie-Louise Lemloh, Eva Weber, Christina Guth, Ingrid M. Weiss	
Contact Angle Analysis of Water Microdroplets on Leaf Surfaces by In-Situ Scanning Electron Microscopy (SEM)	193
M. Koch, N. de Jonge	
Engineering Electrochemical Setups for Electron Microscopy of Liquid Processes	196
E. Jensen, A. Burrows, K. Mølhave	
On the Recent Advancements in In-situ Imaging Catalysts at the Atomic Scale with Aberration-Corrected HRTEM	198
J. R. Jinschek, S. Helveg	
JEOL Clairscope: A Fundamental New Approach of Correlative Microscopy in Bio and Material Science	201
Jürgen Heindl	
Acknowledgments	202
3. Electron Tweezers as a Tool for High-Precision Manipulation of Nanoobjects	203
Vladimir P. Oleshko, James M. Howe	
1. Introduction	204
2. Theoretical Models	216
3. Experimental Schemes	219
4. Plasmon Resonances and Electron Beam Trapping of Nanoparticles	241
5. Outlook and Future Directions	244
Acknowledgments	248
References	249
4. Robustness Analysis of the Reduced Fuzzy Texture Spectrum and its Performance on Noisy Images	263
Pilar Sobrevilla, Eduard Montseny, Aina Barcelo	

1. Introduction	263
2. TS and FTS	268
3. Reduced TS and FTS Encodings	270
4. Performance of FTS versus TS	273
5. Conclusions	286
Acknowledgments	287
References	287
5. Measure-by-Wire (MBW): An Automatic Control Framework for High-Throughput Transmission Electron Microscopy	291
Arturo Tejada, Wouter Van den Broek, Arnold J. den Dekker	
1. Introduction	292
2. The Need for High-Throughput TEMs	294
3. The State of the Art in TEM Automation	305
4. A New TEM Paradigm: Measure-by-Wire	312
5. Examples of the MBW Approach	321
6. Conclusions	335
Acknowledgments	336
Appendix A. Manual to Automated Operation Throughput Ratio	337
Appendix B. Auto-Tuning Methods	339
Appendix C. Estimation of the Second-Order Model Parameters	340
References	341
Contents of Volumes 151–178	347
Index	353



Invariant Quantum Wave Equations and Double Space-Time

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Contents

1. Introduction	3
2. Dirac Equation	7
2.1. Using Dirac Matrices	7
2.1.1. <i>Second-order Equation</i>	8
2.1.2. <i>Conservative Current</i>	9
2.1.3. <i>Tensors</i>	10
2.1.4. <i>Gauge Invariances</i>	11
2.1.5. <i>Relativistic Invariance</i>	12
2.2. The Wave with Pauli Algebra	13
2.2.1. <i>Relativistic Invariance</i>	15
2.2.2. <i>More Tensors</i>	16
2.2.3. <i>Plane Waves</i>	19
2.3. Invariant Dirac Equation	20
2.3.1. <i>Second-order Equation</i>	23
2.3.2. <i>Charge Conjugation</i>	23
2.4. About Pauli Algebra	25
3. The Homogeneous Nonlinear Wave Equation	25
3.1. Gauge Invariances	29
3.2. Plane Waves	30
3.3. Relativistic Invariance	31
3.3.1. <i>Double Space-Time</i>	33
3.4. Wave Normalization	34
3.5. The Hydrogen Atom	35
4. Invariance of Electromagnetic Laws	37
4.1. Maxwell—de Broglie Electromagnetism	37
4.1.1. <i>Invariance Under Cl_3^*</i>	40
4.2. Electromagnetism with Monopoles	43
4.3. Four Photons	45
4.3.1. <i>The Electromagnetism of the Photon</i>	48
4.3.2. <i>Three Other Photons of Lochak</i>	52
4.4. Uniqueness of the Electromagnetic Field	53
4.5. Concluding Remarks	54

5. Electro-Weak and Electro-Strong Interactions	55
5.1. The Weinberg-Salam Model for an Electron	55
5.2. Invariances	66
5.3. Mass and Fifth Coordinate	69
5.4. The Quark Sector	69
5.5. Chromodynamics	75
6. Other Consequences	78
6.1. Anisotropy	78
6.1.1. <i>Three Generations, Four Neutrinos</i>	83
6.2. Torsion	85
6.2.1. <i>Case of a Plane Wave</i>	88
6.3. Systems of Electrons	91
6.4. Equation Without Lagrangian Formalism	93
6.4.1. <i>Plane Waves</i>	94
6.5. Concluding Remarks	95
7. Appendix A—Clifford Algebra	97
7.1. What is Clifford algebra?	98
7.2. Clifford Algebra of an Euclidean Plane: Cl_2	99
7.3. Clifford Algebra of the Physical Space: Cl_3	100
7.3.1. <i>Cross-product, Orientation</i>	101
7.3.2. <i>Pauli Algebra</i>	102
7.3.3. <i>Three Useful Conjugations</i>	103
7.3.4. <i>Gradient, Divergence and Curl</i>	103
7.3.5. <i>Space-Time in Space Algebra</i>	104
7.3.6. <i>Relativistic Invariance</i>	105
7.3.7. <i>Restricted Lorentz Group</i>	106
7.4. Clifford Algebra of the Space-Time: $Cl_{1,3}$	107
7.4.1. <i>Dirac Matrices</i>	108
7.5. $Cl_{2,3}$ Clifford Algebra	110
7.6. $Cl_{3,4}$ Clifford Algebra	111
8. Appendix B—Calculations in Pauli Algebra	113
8.1. Calculation of Tensors	113
8.1.1. <i>Calculation of Ω_1 and Ω_2</i>	113
8.1.2. <i>Calculation of D_μ^ν</i>	114
8.1.3. <i>Calculation of S_k</i>	117
8.2. Various Calculations	121
8.2.1. <i>Proving $\nabla = \widehat{M}\nabla'\widehat{M}$</i>	121
8.2.2. <i>Proving $R_{\nu}^{\mu,\gamma} = \tilde{N}_{\gamma}^{\mu}N$</i>	123
8.2.3. <i>Calculation of $\bar{R}_\mu^\nu$</i>	123
8.2.4. <i>Proving $\det(R_\mu^\nu) = r^4$</i>	125
8.2.5. <i>Relations Between Tensors</i>	127
8.2.6. <i>The Invariant Equation and Lagrangian</i>	128
Acknowledgments	134
References	134



Electron Tweezers as a Tool for High-Precision Manipulation of Nanoobjects

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Contents

1. Introduction	204
1.1. Background	204
1.2. 2-D and 3-D Plasmonic Optical Tweezers	206
1.3. Microfabrication and Nanofabrication by Optical Tweezers and Light-Driven Machines	209
1.4. <i>In Situ</i> Analytical Electron Nanoscopy and Multiple Functionalities of Electron Beams	211
2. Theoretical Models	216
3. Experimental Schemes	219
3.1. Overview of Electron Beam Trapping Experiments	219
3.2. Electron Beam Trapping and Manipulation of Nanoparticles in Liquids	220
3.2.1. <i>Trapping and Manipulation of Nanoparticles in a Liquid Environmental Cell at Room Temperature</i>	220
3.2.2. <i>Manipulation of Solid Nanoparticles in a Molten Alloy</i>	223
3.3. Controlling Movements of Nanoparticles on Thin Film Supports	234
3.3.1. <i>Levitation of a Nanocrystal in a 3-D Coulomb Potential Well</i>	234
3.3.2. <i>Controlled Motion of Small Particles Under an Aberration-Corrected Probe</i>	236
3.3.3. <i>Rotation of Nanoparticles by Vortex Electron Beams</i>	239
4. Plasmon Resonances and Electron Beam Trapping of Nanoparticles	241
5. Outlook and Future Directions	244
Acknowledgments	248
References	249



Robustness Analysis of the Reduced Fuzzy Texture Spectrum and its Performance on Noisy Images

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Contents

1. Introduction	263
2. TS and FTS	268
2.1. TS	268
2.2. FTS	268
3. Reduced TS and FTS Encodings	270
3.1. Obtaining the Membership Functions Defining the N_{FTU}	271
4. Performance of FTS versus TS	273
4.1. Similarity and Dissimilarity Measures	273
4.2. Determining the Size of the Raster Window	276
4.3. Performance and Robustness of the TS and FTS Against Noise	278
4.4. Identifying Textures Belonging to the Same Class	283
5. Conclusions	286
Acknowledgments	287
References	287



Measure-by-Wire (MBW): An Automatic Control Framework for High-Throughput Transmission Electron Microscopy

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Contents

1. Introduction	292
2. The Need for High-Throughput TEMs	294
2.1. Particle Radius Estimation	295
2.1.1. MBW in Particle Radii Estimation	297
2.2. Virtual Nanoscopy	299
2.2.1. MBW in Virtual Nanoscopy	301
2.3. Electron Tomography	303
2.3.1. MBW in Electron Tomography	304
2.4. Further Arguments for High-Throughput TEMs	304
3. The State of the Art in TEM Automation	305
3.1. The State of the Art	305
3.2. The Need for a New Engineering Perspective	309
3.3. Benefits of the Systems and Control Approach	311
4. A New TEM Paradigm: Measure-by-Wire	312
4.1. Systems and Control Concepts	312
4.2. The MBW Concept	313
4.3. Control-Oriented Integration Model	319
5. Examples of the MBW Approach	321
5.1. Defocus Regulation	321
5.2. Specimen Drift Compensation	331
6. Conclusions	335
Acknowledgments	336
Appendix A. Manual to Automated Operation Throughput Ratio	337
Appendix B. Auto-Tuning Methods	339
Appendix C. Estimation of the Second-Order Model Parameters	340
References	341